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... the resistivities of the **semiconductor**. The energy band shifts are also influenced ... compressive **stress** on pn-junction **device** current. This ...
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W Dobrowolski, RR Galazka, E Grodzicka, J Kossut, ... - Phys Rev B, 1993 - link.aps.org
... is expected to lead to a better **device** perfor- mance ... of the conduction band in a narrow-gap **semiconductor**. ... Let us **stress** that in the latter samples doped only ...
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Q Wei, J Narayan - International Materials Reviews, 2000 - ingenta.com
... techniques of **fabrication**, theoretical modelling, ... frac- tion, density, and internal **stress** are directly ... density, thermal conductivity, etc.) **properties** of the ...
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... supports or interfaces with an- other material or **device** to form ... **PROPERTIES** OF GLASS SURFACES ... interesting type of yield behavior when the **stress** conditions are ...
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... MWNTs, it is useful to briefly highlight the important electronic **properties** of the ... electrons, a material can in general be either a metal or a **semiconductor**. ...
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1 Special issue: AI in engineering

D. Sriram, R. Joobbani

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The papers in this special issue were compiled from responses to the announcement in the July 1984 issue of the SIGART newsletter and notices posted over the ARPAnet. The interest being shown in this area is reflected in the sixty papers received from over six countries. About half the papers were received over the computer network.

2 RAID: high-performance, reliable secondary storage

Peter M. Chen, Edward K. Lee, Garth A. Gibson, Randy H. Katz, David A. Patterson

June 1994 **ACM Computing Surveys (CSUR)**, Volume 26 Issue 2

Full text available: pdf(3.60 MB) Additional Information: full citation, abstract, references, citings, index terms, review

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Keywords: RAID, disk array, parallel I/O, redundancy, storage, striping

3 Research directions in virtual environments: report of an NSF Invitational Workshop, March 23-24, 1992, University of North Carolina at Chapel Hill

Gary Bishop, Henry Fuchs

August 1992 **ACM SIGGRAPH Computer Graphics**, Volume 26 Issue 3

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Jim Foley

June 1994 **Proceedings of the workshop on Advanced visual interfaces**

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5 A unified approach to test data analysis

Michael A. Gianfagna

June 1978 **Proceedings of the 15th conference on Design automation**

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To provide cost-effective performance evaluation or engineering feedback from circuit test results often requires that complex analyses be performed on large volumes of non-standard data. Using a large scale data management system and a modular design philosophy, a system to cope with the above requirements has been developed. TDAS (Test Data Analysis System) has provided timely and economic solutions to test data analysis problems which might have been intractable by other means.

6 Quo Vadimus: computer science in a decade

J. F. Traub

June 1981 **Communications of the ACM**, Volume 24 Issue 6

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A panel discussion was held during the third biennial meeting of chairmen of Ph.D.-granting computer science departments in June, 1978 at Snowbird, Utah, a meeting sponsored by the Computer Science Board. Invitees from industry and government were also present. A report was prepared from tapes made of the discussion (Department of Computer Science, Carnegie-Mellon University: Report #CMU-CS-80-127, June 1980). It contained all the prepared statements of the panelists, lightly edited, and th ...

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I De Wolf - Semicond. Sci. Technol, 1996 - iop.org
... In the absence of **stress**, the corresponding three optical Raman modes of silicon have ... see section 2.4.) From a quantum **physical** point of view, Raman scattering ...
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Transport properties of Hg Zn x Se and Hg Mn x Se doped with Fe resonant donors
W Dobrowolski, RR Galazka, E Grodzicka, J Kossut, ... - Phys Rev B, 1993 - link.aps.org
... 17 848 1--" 1993 The American **Physical** Society TRANSPORT ... of the conduction band in a narrow-gap **semiconductor**. ... Let us **stress** that in the latter samples doped ...
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Q Wei, J Narayan - International Materials Reviews, 2000 - ingenta.com
... sp3 frac- tion, density, and internal **stress** are directly ... **physical** (heat capacity, density, thermal conductivity, etc.) **properties** of the material. ...
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... interfaces with an- other material or **device** to form ... These cleavages are instances of the **physical** reality (22 ... of yield behavior when the **stress** conditions are ...
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... proper charge compensation while the **semiconductor** cannot, making ... review of recent advances in **physical** vapour growth ... PbTiO 3 and their **device** applications by ...
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M Silver, EP O'Reilly, AR Adams - IEEE J. Quantum Electron, 1997 - ieeexplore.ieee.org
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... output from SiGe structures is **based** on the ... in cooperation with the Institute for **Semiconductor** Physics at ... strain calculations are required to **calculate** of the ...
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... DRAM) and complementary metal oxide **semiconductor** (CMOS) ... are generated will degrade device **performance** [5, 6 ... attainable pitch lengths of LOCOS-**based** technologies ...
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... The second step was to make a 1/10-scale model test to **simulate** the air ... The design was **based** on the earlier studies, and the earlier flow- pattern results were ...
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